		•	!	Docket	Docket Number AD-303J Applicati			n Number 10/090,941		
INFOR	MATIC	ON DISCLOSURE CITATIO	Applicants Stein et al.							
			!	Filing	Filing Date Art Unit					
			U.S. PATENT	י חטכעו	March 5, 2002 MENTS		218	33		
*EXAMINER INITIALS	REF	DOCUMENT NUMBER	PUBLICATION		NAME OF PATENTEE OR APPLI		FILING	DATE IF APPROPRIATE		
	1	6,587,864 B2	07/01/2							
1					Stein et al.		 			
OVPE	2	6,434,662 B1	08/13/2	.002	Greene et al.		<u> </u>			
SEP 1 2 70173	3	6,349,318 B1	02/19/2	.002	Vanstone et al.					
	4	6,246,768 B1	06/12/2	2001	Kim	Kim				
TO THE DEVICE	5	6,230,179 B1	05/08/2	2001	Dworkin et al.	Dworkin et al.				
	6	6,199,087 B1	03/06/2	:001	Blake et al.	Blake et al.				
	7	6,199,086 B1	03/06/2	:001	Dworkin et al.	Dworkin et al.				
	8	6,049,815	04/11/2	:000	Lambert et al.			DEOCN/CD		
	9	5,689,452	11/18/1	1997	Cameron			EIVED		
1	10	5,446,850	08/29/19	995	Jeremiah et al.			0 4 7003		
WMT.	11	5,379,243	01/03/19	995	Greenberger et al.	Tech	nology	Center 2100		
		T	FOREIGN PATE	NT DOC	CUMENTS					
ş	REF	FOREIGN DOCUMENT NUMBER	PUBLICATION DA	ATE	COUNTRY		Transli	lation		
						YES	,	МО		
Tuy	12	EP 1 246 389 A1	10/02/2002	2	Europe					
								·		
	•			1				· · · · · · · · · · · · · · · · · · ·		
			OTHER DO	CUMEN.	TS (Including Author, Title, Date, I	Pertinent Pag				
WMT 1	13	Viktor Fischer, Realization http://csrc.nist.gov/Crypto	of the Round 2 oToolkit/aes/re	2 AES (Candidates Using Altera FP(onf3/papers/24-vfischer.pdf>	<i>GA</i> , (Janus > (Microni	ıry 26, 1 ic - Kos	2001) ice, Slovakia).		
1	14	Máire McLoone and J.V. M Implementations, CHES 200	1cCanny, <i>Higl</i> 01 PROC, LNC	h Perfoi S 2162	ormance Single-Chip FPGA R 2, 65-76 (Ç.K. Koç et al. eds.	Rijndael Al 16 May 20	gorithm 001).	:		
EXAMINER W		REAT			E CONSIDERED 12/2/					
XAMINER: Initial if	citation c	considered, whether or not citation	is in conformanc	e with M	IPEP Section 609; Draw line throu	gh citation if	not in co	nformance and		

BEST AVAILABLE COPY

Form PTO-A820 (also form PTO-1449)

INFORMATION DISCLOSURE CITATION					AD-303J	10/090,941			
					Stein et al.				
				Filing I	Date March 5, 2002	Art Unit	rt Unit 2183		
		·	U.S. PATENT	DOCUN					
*EXAMINER INITIALS	INITIALS REF DOCUMENT NUMBER			N DATE	NAME OF PATENTEE OR APPLIC	CANT	FILING	DATE IF APPROPRIATE	
WINT	15	5,214,763	05/25/1	993	Blaner et al.				
OTPE		5,095,525	03/10/1	992	Almgren et al.				
SEP 0 2 2003	3 17	4,918,638	04/17/19	990	Matsumoto et al.				
	18 4,852,098		07/25/19	989	Brechard et al.				
PADEMIE	19	4,847,801	07/11/1	989	Tong				
	20	4,722,050	01/26/1	988	Lee et al.				
	21	3,805,037	04/16/19	974	Ellison				
	22	US 2003/0149857 A1	08/07/20	003	Stein et al.	Stein et al.			
	23	US 2003/0140213 A1	07/24/20	003	Stein et al.				
	24	US 2003/0140211 A1	07/24/20	003	Stein et al.			,	
MMT	25	US 2003/0133568 A1	07/17/20	003	Stein et al.				
······································		F	FOREIGN PATEN	NT DOC	CUMENTS				
	REF	FOREIGN DOCUMENT NUMBER	PUBLICATION DA	ATE	COUNTRY			station	
				-		YES		ю	
				+		RFI	CFI	/ED	
				+			• • • • •		
				-		-	0 4		
				_		16CH IOIU	gy voi	ter 2100	
			OTHER DO	CUMEN	TC (Including Author Title Date)	Partitions Page	5m)		
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) 26 elixent, Changing the Electronic Landscape (2001) http://www.elixent.com (elixent - Bristol, UK).									
Trust		thating their are area.	Mic Lumascap	/E (200.	1) Suttp://www.chacut.com	, (enrem -	Dristo	I, UK).	
mm	27	elixent Application Note <i>JPI</i> (elixent - Bristol, UK).	EG Codec (De	c. 9, 20	002) http://www.elixent.com/	m/assets/jp	eg-cod	ler.pdf>	
	W.	TREAT			E CONSIDERED 12/2/	104			
XAMINER: Initial i ot considered. Inclu	if citation ide copy o	considered, whether or not citation of this form with next communication	is in conformance n to applicant.	e with M	IPEP Section 609; Draw line throug	gh citation if	not in co	informance and	

Form PTO-A820 (also form PTO-1449)

Patent and Trademark Office * U.S. DEPARTMENT OF COMMERCE

INFORMATION DISCLOSURE CITATION					Docke	et Number AD-303.	Application	on Number , , . 10/090,941		
					Applic	Applicant Stein et al.				
						Date March 5, 2002	Art Unit	2183		
				U.S. PATENT	r DOC U	MENTS				
*EXAMINER INITIALS	AMINER INITIALS REF DOCUMENT NUMBER		PUBLICATIO	ON DATE	· NAME OF PATENTEE OR APPL	ICANT	FILING DATE IF	APPROPRIATE		
MAT	28 US 2003/011		003/0115234 A1	3/0115234 A1 06/19/2		Stein et al.				
OIPE	29	US 2003/0110196 A1		1 06/12/2	2003	Stein et al.				
SEP 0 2 2003	3 30	US 20	US 2003/0105791 A1		2003	Stein et al.				
4	us 2003/0103626 A		03/0103626 A1	1 06/05/2	2003	Stein et al.				
RADELLE!	32	US 20	002/0147825 A1	1 10/10/2	2002	Stein et al.				
	33	US 20	002/0041685 A1	l 04/11/2	2002	McLoone et al.				
	34	34 10/440,330				Stein et al.		05/16/2003		
THE	35	1	10/395,620			Stein et al.		03/24/2003		
			*							
				FOREIGN PATE	NT DO	CUMENTS				
	REF	FOREIGN DOC	UMENT NUMBER	PUBLICATION DA	ATE	COUNTRY		Translation		
							YES		NO	
		<u> </u>					-			
				 			 			
				<u> </u>			<u> </u>			
	·	<u>. </u>		l						
				OTHER DO	CUMEN	NTS (Including Author, Title, Date,	Pertinent Pag	es, Etc.)		
hur	36	V. Baumgar <a href="http://www</td><td>te et al., PACT
v.pactcorp.com</td><td>XPP - A Self-l
/xneu/downlo</td><td>Reconf.
ad/ers2</td><td>figurable Data Processing Art
a01.pdf> (PACT XPP - Santa</td><td>chitecture (
a Clara, Ca</td><td>June 2001)
A).</td><td></td></tr><tr><td>TMW</td><td>37</td><td>PACT Infor <a href=" http:="" td="" www.new.new.new.new.new.new.new.new.new.<=""><td>mationstechnov.pactcorp.com</td><td>logie GmbH, 7</td><td>The XP ad/xpp</td><td>PP White Paper Release 2.1 (white_paper.pdf> (PACT)</td><td>March 27, 2 XPP - Sant</td><td>2002) a Clara, CA).</td><td></td>	mationstechnov.pactcorp.com	logie GmbH, 7	The XP ad/xpp	PP White Paper Release 2.1 (white_paper.pdf> (PACT)	March 27, 2 XPP - Sant	2002) a Clara, CA).		
XAMINER		W. 5	REAT		DAT	E CONSIDERED 12/2/04				
XAMINER: Initial interest includes	if citation	considered, whe		n is in conformant	ce with N	MPEP Section 609; Draw line throu	igh citation if	not in conforma	nce and	

Form PTO-A820 (also form PTO-1449)

Patent and Trademark Office * U.S. DEPARTMENT OF COMMERCE